## TG3: Analog Electronics for Ge detectors

Goal of Task Group: Delivery of

- Front-end (FE) circuts for Ge det. read-out
- Cables from FE to FADC
- HV-PS, LV-PS, Pulser

• Slow-control of operational parameters of digital and analog electronics.

#### Status of TG3 works: FE not ASIC cryogenic circuits

	Status / meet specs	Date	Notes
Test of FE Circuit 1 (AGATA, discrete components)	Achieved	09/05	Discrete components. Warm outside LN bath with cold FET
Test of FE Circuit 2 (IPA4 – monolithic JFET+ polarizing components) Production of 20 FE channels for Ge prototypes at LNGS and MU	Achieved Achieved	02/2005 05/2006	Semi-integrated. Polarizing components, CF,RF not integrated.
Test of produced channels	To be done	07/2006	
Test of FE circuit 3 (AMPTEK- A250)	$\checkmark$	12/2005	Ibrid can work at cryo-T.

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# Status of TG3 works: ASIC FE cryogenic circuits

MI- ASIC – CMOS FE			Integrated but not CF,RF
Test	Achieved	06/2005	
Test of chips	Achieved	12/2005	
2 <sup>nd</sup> run (fine tuning)	To be done	10/2006	
Production	To be done	2007	
MI- ASIC – CMOS FE			Fully Integrated but not RF,
Test run	Submitted	07/2006	with possible active reset
Test of chips	TBA	09/2006	
2 <sup>nd</sup> run (tuning)	TBA	10/2006	
Packaging	Candidate	04/2006	
Hd ASIC-CMOS			Fully integrated
Test run	Done	02/2006	
Test of chips	TBA	?	
2 <sup>nd</sup> run	TBA	?	
Production	TBA	2007	
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	Status / meet specs	Date	Notes
HV for Ge detector Caburn Kapton 8 kV 0,25 mm diam	Achieved	06/05	Measured by M.Laubenstein < 10 mBq/kg both for U and Th. (30 g/ 6 m)
Signal (from FE to FADC) and LV PS (picocoax-Axon) (siltem coax) (Tekdata woven)	X Ongoing, candidates exists	12/2005 05/2006	To be measured γ- spectrometry
LV PS	Candidate	07/2006	INFN-PD design and production
HV PS	Candidate		
Pulser	X	12/2006	

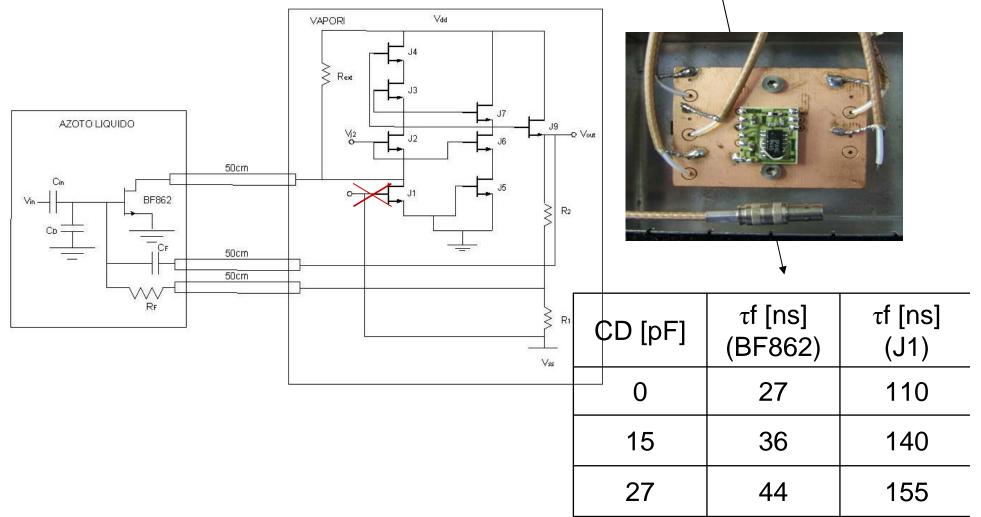
#### Status of TG3 works : Cables (Phase I) and LV,HV PS

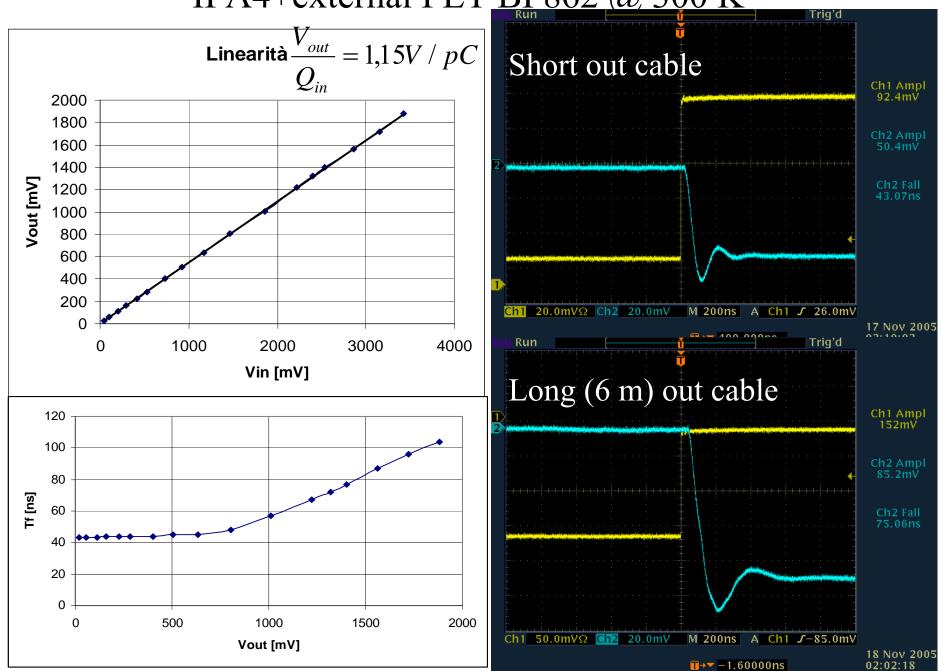
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# Possible problems

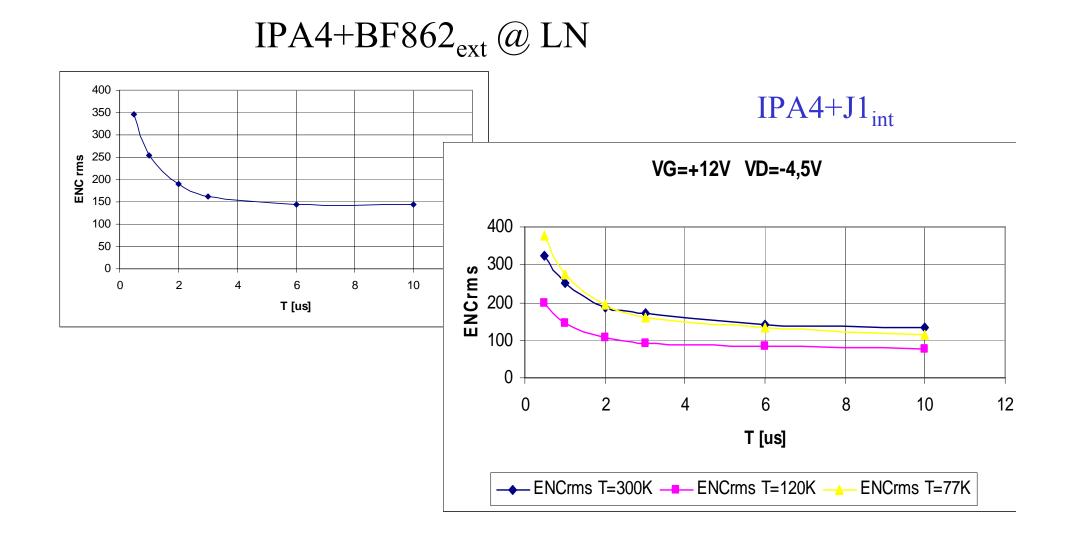
Too high radioactivity of components, as the junction box has to be put nearest the top of the crystal string compared to the showed solution (see talk of B.Majorovits)

# IPA4+external FET BF862: Why?

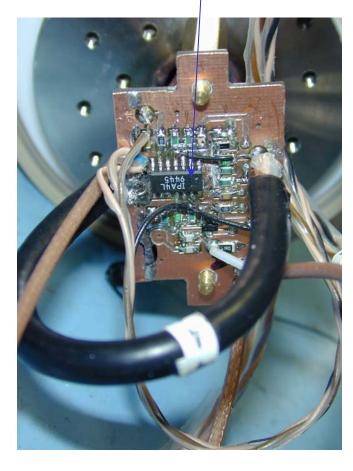




# IPA4+external FET BF862 @ 300 K



#### IPA4 + $J1_{ext}$ + 100 $\Omega$ Out stage: the new test board

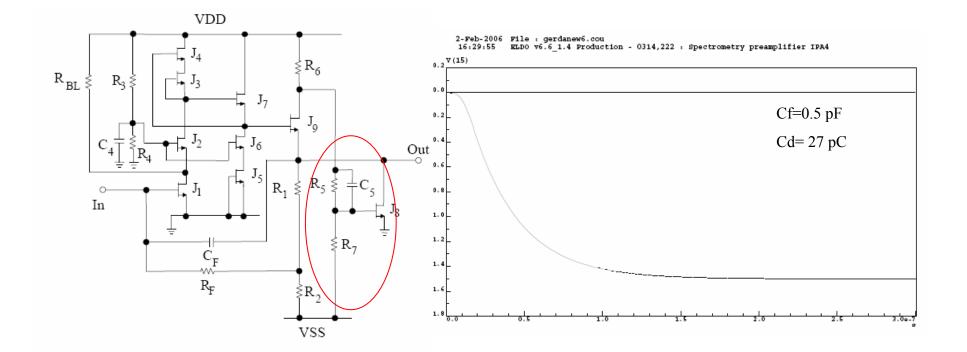


New setup for LN measurements



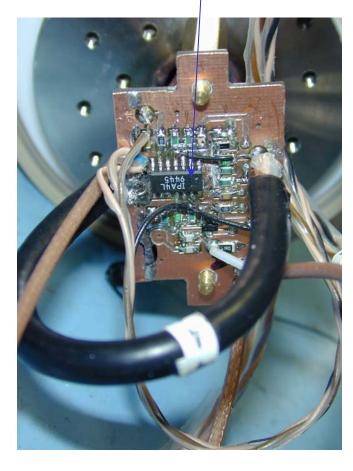
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#### IPA4 + $J1_{ext}$ + 100 Out stage: simulated pulse 50 ns fall time (@ 300 K).



Swing to -1.5 V

#### IPA4 + $J1_{ext}$ + 100 $\Omega$ Out stage: the new test board

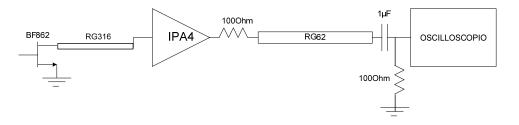


New setup for LN measurements



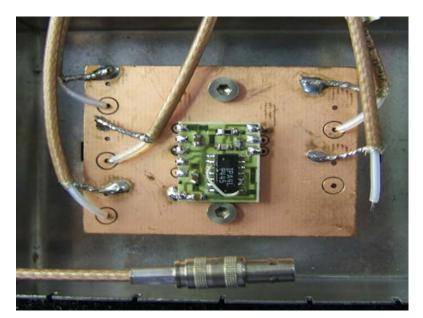
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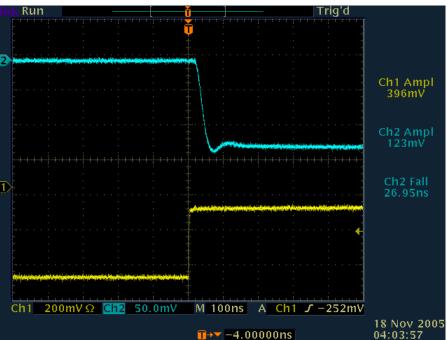
# Back to 1 k $\Omega$ out stage, better pulse shape



Measured pulse fall time for IPA4 preamp. Operated with integrated J1 or external BF862, at T=LN.

CD [pF]	τf [ns] (BF862)	τf [ns] (J1)
0	27	110
15	36	140
27	44	155





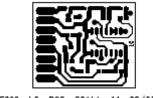
Production of 20 FE cryogenics circuits (based on IPA4 JFET monolithic circuit) for MU 18 fold segmented prototype, and for LNGS Phase I detector tests

Production of PCB: 23 june at AREL, without 100  $\Omega$  output stage: Lowest dissipation and not perfect shape

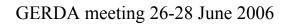
Mounting of components: this week (end 30 june provided I send components).

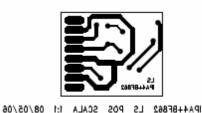
For LNGS test: 2-3 channels

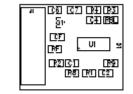
For MU 18-fold crystal: test and mount circuits on mother board to host 20 preamps and signal-in signal-out. Ready to work endjuly.



IPA4+BF882 LC POS SCALA 1:1 08/05/06







IPA4+BF862 LC POS SCALA 1:1 08/05/06

# Charge Preamplifier and Fully Differential Line Driver Integrated in AMS CMOS 0.8um CXZ Tech. for the GERDA Experiment

Milan University and I.N.F.N.

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# Input transistor

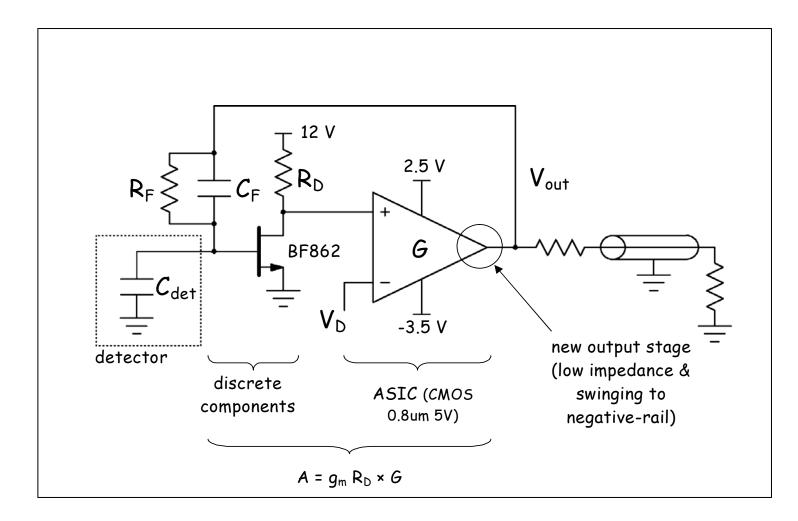
# External (JFET e.g. BF862)

- Noise <u>is</u> adequate
- Bandwidth is adequate
- Transistor <u>can</u> be replaced
- Can work at  $V_{GS} = 0$  V which helps zeroing the output offset
- Power consumption is high

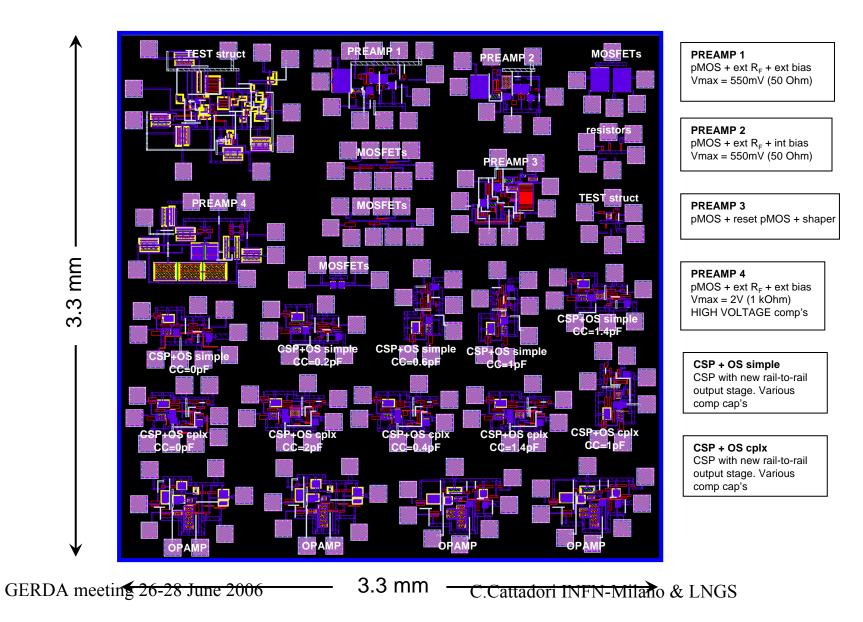
### Integrated (p-MOSFET)

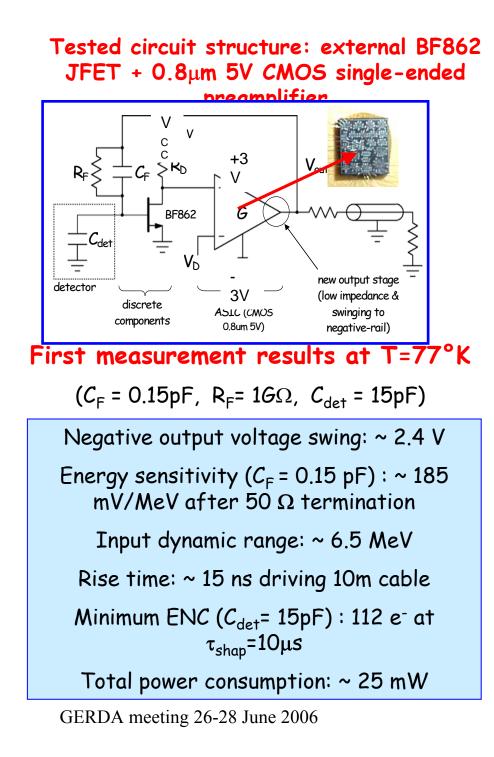
- Noise <u>could</u> be adequate
- Bandwidth is adequate
- Transistor <u>cannot</u> be replaced
- Transistor cannot work at V<sub>GS</sub> = 0
  V
- Power consumption of p-MOSFET could be lower

#### Proposed circuit structure (from J. Gal\*)

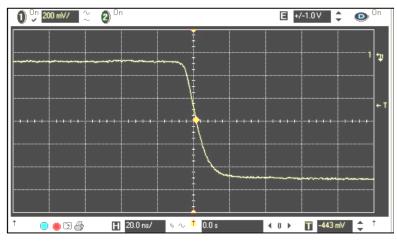


# Test chip

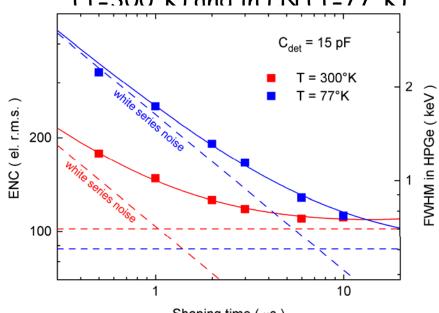




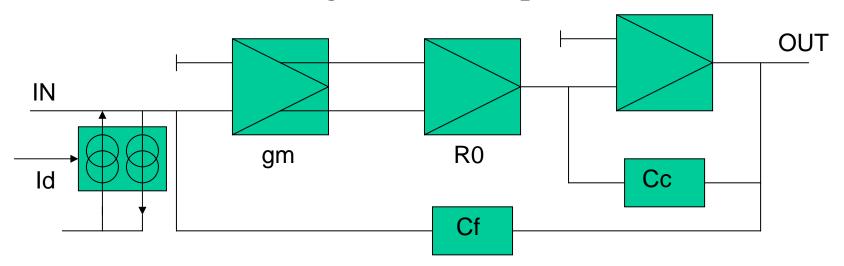
#### Acquired output signal driving a 50 $\Omega$ coaxial cable of ~ 10 m : rise time of ~ 15 ns



Comparison between **noise measured** at room temperature (T=300°K) and in LN (T=77°K)

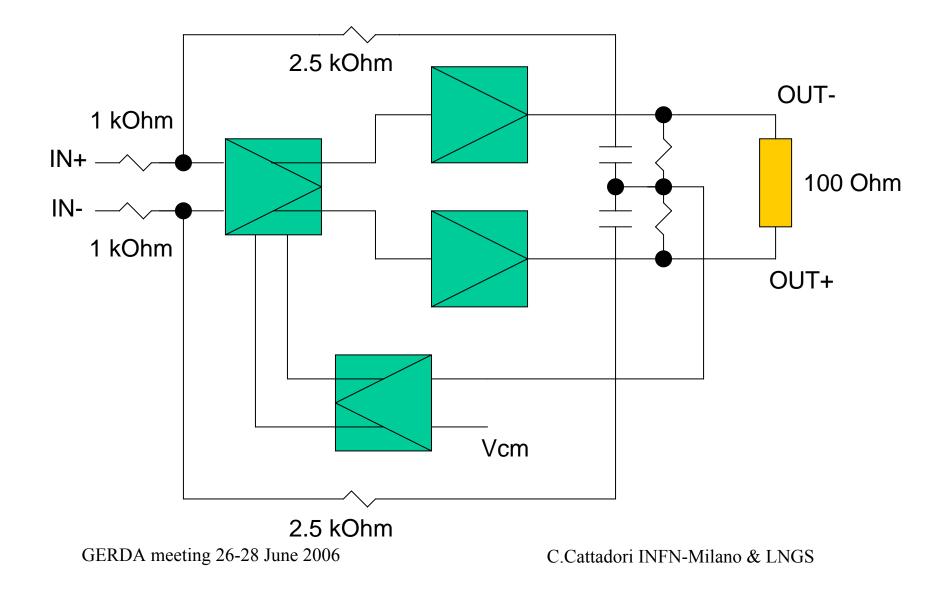


### **Integrated Preamplifier**



- Tunable system (variable gm and R0 by a factor of 10)
- Noise, bandwidth according to specifications
- Dual Power Supply (+2.5v / -2.5v) / No additional Vrefs required
- Fully Bipolar Output Swing (+1.6v / -1.6v) @ Rload = 1 Kohm
- Non linearity < 1/1000 @ (-1.6v < Output Swing < +1.6v)
- Can operate with continuous reset (external R) or pulsed reset (bipolar Id)

### Fully Differential Line Driver



## Fully Differential Line Driver

- Dual Power Supply (+2.5v/-2.5v)
- No additional Vrefs required
- Fully Differential Signal Path inside the OpAmp
- Fully Bipolar Output Swing (+2v/-2v) @ Rload = 100 Ohm
- Large Differential Output Swing (8v) @ Rload = 100 Ohm
- Bandwidth according to specifications
- Tunable system
- Variable Power Consumption: (from 3 mA @ Low Power up to 6 mA @ Full Bandwidth)

#### Low Voltage Low Noise PS designed at PD –INFN workshop V=+12 V, V=+5 V, V=-5 V, I = 0.7 A each)

# If test OK then can be adopted for GERDA







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